


<b>Search Notes</b> 	<b>Application/Control No.</b> 10511378	<b>Applicant(s)/Patent Under Reexamination</b> BEYER ET AL.
	<b>Examiner</b> Kianni C Kaveh	<b>Art Unit</b> 2883

SEARCHED			
Class	Subclass	Date	Examiner
385	28, 18, 140	2/26/08	kck

SEARCH NOTES		
Search Notes	Date	Examiner
Searched through EAST: USPGPUB, USPAT, EPO, JPO and DERWENT and NPLSearched inventorship through PALMSearched class 385	2/26/08	kck

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
385	28, 18, 140	2/26/08	kck